Prober Mercury Probe

**Short description:** Mercury Probe is probing device to make rapid, non-destructive contact to a sample for electrical characterization. It makes the contact with the substrate with a concentric dot and ring mercury electrode and backside contact. Its primary application is semiconductor measurements, without performing the time consuming metallization and photolithographic processing. It can be used to perform various C-V and I-V measurement on MOS samples, semiconductor doping etc.

Center contact diameter : 907µm
Stray capacitance : 1.8pF

**Localisation:** Welcome

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